

Scanning μ -squid Force Microscope

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A novel scanning probe technique is presented: Scanning μ -SQUID Force microscopy (SSFM). The instrument features independent topographic and magnetic imaging. The SSFM operates in a dilution refrigerator in cryogenic vacuum. Sample and probe can be cooled to 0.45 K. The probe consists of a μ -SQUID placed at the edge of a silicon chip attached to a quartz tuning fork. A topographic vertical resolution of $0.02 \mu\text{m}$ is demonstrated and magnetic flux as weak as $10^{-3}\Phi_0$ is resolved with a $1 \mu\text{m}$ diameter μ -SQUID loop.

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I. INTRODUCTION

A recent review [1] on local magnetic probes describes different techniques used for room temperature as well as for low temperature magnetic imaging. Several important points have to be considered conceiving a scanning magnetic probe microscope: Magnetic sensitivity and spatial resolution are determined by the probe, the sample and the distance between them. It has been observed [1] that the sensitivity to the magnetic field, in units of tesla, increases with probe size, but at the same time spatial resolution diminishes. The distance between sample and probe must be as small as possible in order to improve the magnetic coupling between them. Therefore the control of this distance becomes an important aspect for a scanning magnetic probe microscope (SMPM). The choice of probe and of distance control depends on the applications of the microscope. The main application of our microscope is the observation of vortices in superconductors at low temperature.

In a superconductor each vortex carries a quantized flux of $\Phi_0 = h/2e = 2 \cdot 10^{-15} \text{ Wb}$. The magnetic size of a vortex is given by the penetration length, λ , setting the length scale over which the screening currents circulate around the normal vortex core. The typical penetration length is of the order of 100 nm at low temperature, it increases with temperature, to finally diverge at T_c . The spatial resolution of a SMPM imaging vortices can hardly be better than λ . The probe should be of size λ or smaller and the scan height less than λ in order to avoid convolution effects. The distance between probe and sample must be controlled using a technique compatible with the cryogenic environment, heating neither sample nor tip.

MFM microscopes have been built for imaging vortices in superconductors at temperatures as low as 4.2 K using either optical [2] or piezoresistive [3] detection schemes. Scanning Hall probe microscopy [4] images vortices at temperatures above 5 K with a STM based technique to control the approach. Very successful SQUID imaging

has been done using mechanical translation without a separate approach control [5] - [9]. A scanning SQUID susceptometer [10] has also been presented, using a piezoelectric scanner and a capacitive technique to control the approach.

In several near field microscopes [11]-[16] the piezoelectric effect has been used recently to measure the minute forces between tip and sample. The tip is attached to the piezoelectric element, and the assembly is excited at its mechanical resonance. Upon approach, due to the surface forces, the resonance frequency increases and the amplitude of oscillation decreases. Shear forces are sensed when the tip oscillates at constant height parallel to the sample's surface, and contact forces appear when the tip oscillates perpendicular to the surface. Near field scanning optical microscopes have been built [12], taking advantage of the high quality factor of piezoelectric quartz crystals. An optical fiber is attached to one prong of a quartz tuning fork and the shear forces are measured. Even a small STM tip [13], [14] can be attached to the tuning fork in order to combine AFM and STM techniques in a contact force geometry. It has been shown that this detection scheme can be used at temperatures as low as 2.2 K [15] and in high magnetic fields.

We built a scanning μ -SQUID force microscope (μ -SQUID -FM) operating inside a dilution refrigerator. A quartz tuning fork senses the contact forces between the tip of the μ -SQUID chip and the sample's surface. The instrument has high magnetic spatial resolution, works at temperatures as low as 0.45 K and is capable of acquiring simultaneously topographic and magnetic images. This microscope is to our knowledge the first magnetic probe microscope working at such low temperatures.

II. MICROSCOPE SETUP

The reversed dilution refrigerator [17] is inside a cylindrical vacuum chamber of 400 mm height and 200 mm

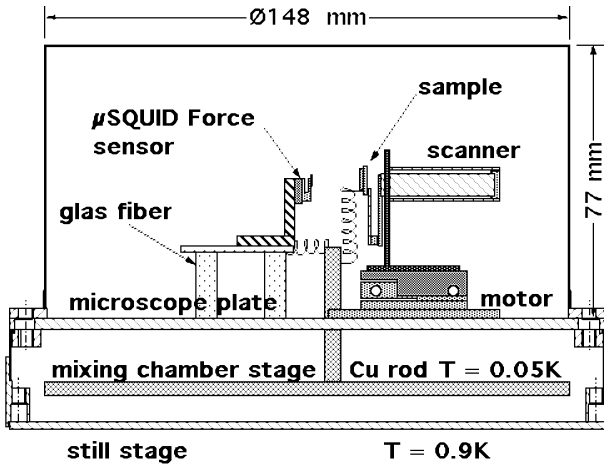


FIG. 1: Schematic drawing of the Scanning μ -SQUID Force Microscope inside the reversed dilution refrigerator. The microscope plate is mounted on the screens of the still stage, sample and μ -SQUID Force sensor are thermalized at the mixing chamber through silver foil and a copper.

diameter. The refrigerator's base temperature is 25 mK with $30 \mu\text{W}$ of cooling power at 100 mK. The refrigerator is anchored to a concrete slab mounted on air suspension and a helium dewar is attached underneath, feeding the 4.2 K pot of the refrigerator by a continuous flow of liquid He. Still and mixing chamber are above the 4.2 K stage. The magnetic field is applied by external Helmholtz coils. The SSFM is mounted on a copper plate fixed to a screen of the dilution refrigerator. On the plate, Fig. 1, is a linear piezoelectric motor carrying a large range scanner [18] with the sample. In front of the scanned sample is the immobile μ -SQUID Force sensor. The microscope plate, Fig. 1, is either flanged to copper screens of the 4.2 K stage or - of the still stage, stages with sufficient cooling power to absorb the energy dissipated during the coarse approach. The sensor is mounted on three glass fiber tubes, isolating it thermally from the plate. The sample is weakly coupled to the main body of the microscope as the ceramic pieces of the scanner have poor thermal conduction. Silver foil thermal links connected to the mixing chamber through a copper rod, allow us to cool sample and μ -SQUID. Sample and μ -SQUID reach a base temperature of 0.45 K while the still is at 0.9 K.

The linear motor is made of titanium and driven by four piezoelectric tubes. The piezoelectric tubes are controlled by an arbitrary wave form generator whose output is amplified by (APEX PA15) amplifiers. The voltage amplitudes can be as high as 200 Volt. We incorporated a capacitive displacement sensor between the base and the mobile part of the motor, allowing us to follow in situ the motor's displacement. The sensor is based on the principle of a three terminal capacitive bridge used for dilatometers [19] or displacement sensors [20]. The sensor has a resolution of the order of 10 nm.

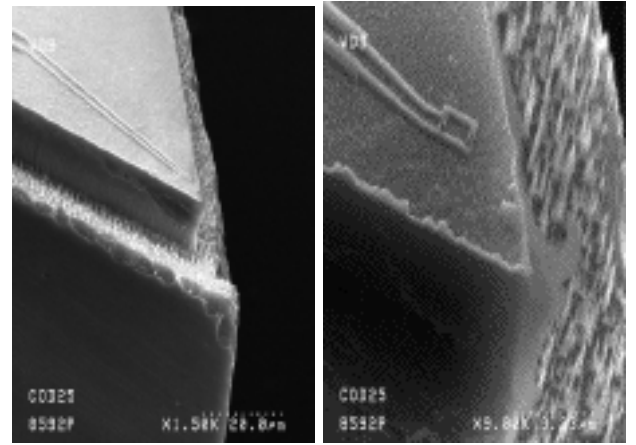


FIG. 2: SEM pictures of the μ -SQUID sensor. left: Overview, the bulk Si is cut with a dicing machine at an angle of 25 degrees. Current leads and the small μ -SQUID loop are visible on the mesa. right: The μ -SQUID sensor of $1 \mu\text{m}$ diameter is closely aligned to the etched mesa, the μ -bridge junctions can be distinguished.

III. PROBE

In order to obtain high spatial magnetic resolution with the microscope we chose as detector a $1 \mu\text{m}$ diameter DC-SQUID, a μ -SQUID. The Josephson Junctions of these μ -SQUIDS are composed of Dayem bridges of 300 nm length, 20 nm width and 30 nm thickness. The width of a μ -SQUID branch is 200 nm. Advantages of these μ -SQUIDS are numerous: they are easily manufactured (only one single level of e-beam lithography is necessary) and the flux pinning is weak as the line width is very narrow. A magnetic flux change is detected by the SQUID through a change in critical current: the μ -SQUID is biased with a DC-current ramp which is reset to zero when the critical current is reached and the μ -SQUID becomes superconducting again [21], [22]. The duration of the ramp is measured, it is proportional to the critical current of the μ -SQUID. The ramp is repeated every 1.6 ms. The μ -SQUIDS made of Nb are used for "high" temperature or high field applications but for high resolution measurements Al μ -SQUIDS are preferable [21]. The magnetization reversal of a 25 nm diameter ferromagnetic cobalt particle [23] has been studied using a μ -SQUID. The particle was placed on the μ -bridge. This is the place for optimal flux linkage between a very small flux source and the μ -SQUID. Elsewhere most of the particle's flux closes [21] upon itself before it intersects the μ -SQUID.

This example has illustrated the importance of proximity between sample and probe. For microfabricated probes the objective of high spatial resolution can only be achieved if they are placed on the very edge of their support and if an appropriate distance control is used. First we describe our probe fabrication and then we present the distance control employed. 50 probes are fabricated on a 2 inches diameter Si wafer. Each μ -SQUID chip is

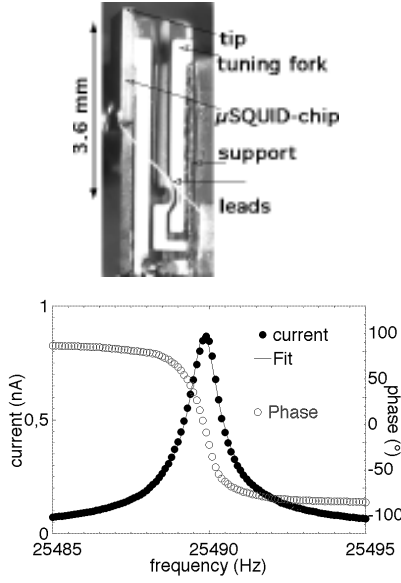


FIG. 3: left: the tuning fork carrying the μ -SQUID-chip. One side of the tuning fork is attached to a fiberglass support. The sensor is oriented nearly parallel to the sample's surface. right: Phase and amplitude measured at 0.45 K of a tuning fork carrying a μ -SQUID-chip, excited mechanically at resonance. The quality factor of the resonance is 17700. The line corresponds to the fit, equation 1.

precision cut [24] with a dicing machine. A precision of 5 μm is obtained, limited only by chipping of the Si. The typical distances between tip and μ -SQUID is between 5 and 15 μm . The distance between μ -SQUID and sample can be reduced further if the point of contact is closer to the μ -SQUID. This can be obtained by dry etching the Si substrate: The μ -SQUID is covered by an insulator (SiC or Si_3N_4) and then a PMMA mask is fabricated with the JEOL 5DIU electron-beam writer leaving open only the μ -SQUID. A thick Al film is deposited and the resist mask is then lifted, leaving an Al mask on the μ -SQUID. The following RIE etch [25] removes vertically 5 to 10 μm of the insulating layer and the unprotected Si. The Al mask is removed by wet etching. The μ -SQUID is situated at the edge of a mesa, Fig. 2. The etched apex close to the μ -SQUID serves now as tip for distance control and topographic imaging. The distance between μ -SQUID and tip is reduced to 2 or 3 μm . For a 3 μm distance between tip and μ -SQUID and an approach angle of 5 degrees the distance between μ -SQUID and sample is 0.26 μm .

The proximity between μ -SQUID and sample needs a good control of the tip-sample distance. Three choices are possible: either tip and sample are continuously in contact or a distance sensor is incorporated and a feedback loop is used, or scanning takes place at constant height above the sample's surface. We have chosen to control distance with a detector sensitive to surface forces. The force sensor should have power consumption in the nW range in order to be compatible with low temperature applications and to be easily adapted to a dilu-

tion refrigerator. We use a tuning fork distance control for the scanning μ -SQUID Force microscope allowing us to separate the μ -SQUID sensor development and the distance control. The tuning fork is a 6 mm long, 0.35 mm wide quartz watch crystal. Each tine is 3.7 mm long and 0.63 mm high. It is designed for a resonance frequency of 32765 Hz at room temperature. Scanning probe schemes [12]-[16] were developed using tuning forks for near field scanning optical microscopy or AFM.

In our case the μ -SQUID-chip of 2.5 mm length weighs about 30 % of the mass of one prong and electrical connections to the μ -SQUID have to be made. We choose to epoxy one prong to the support while the other prong carries the Si chip on which the μ -SQUID is fabricated. The chip is glued on the prong and covers about two third of the free length of the tine, Fig. 3 left. Two AlSi wires of 33 μm diameter are wedge-bonded onto the chip to connect the μ -SQUID electrically. The tuning fork is mechanically excited with a thickness mode piezoelectric crystal nearby and the generated current is amplified at room temperature with a preamplifier of gain $35 \cdot 10^{-9}$ A/V.

The resonance frequency of the tuning fork is shifted from 32.7 kHz to about 25 kHz by the extra mass of the Si chip. Knowing the Young's modulus of quartz, and using the expression of the spring constant of a beam of given dimensions, a spring constant of the order of 36000 N/m is obtained for the bare tine. The frequency variation of the electrical current, $I(f')$, through the tuning fork can be fitted by the Lorentz form of a serial (RLC) resonator as expressed in equation 1. The quality factor of the resonator is defined as $Q = \frac{f}{\Delta f}$, with Δf the width of the resonance at half height. The Q-factor for our resonators is of the order of 100 to 200 at room temperature in air and 10000 to 20000 at 0.45 K.

$$I(f') = \frac{I_0 f'}{\sqrt{f'^2 + 3Q^2(1 - f'^2)^2}} + I_{base} \quad (1)$$

where, $f' = \frac{f}{f_{res}}$ is the reduced frequency and I_0 is the current amplitude at resonance. The quality of the adjustment indicates that the mechanical properties of our probe can be described by this simple model despite the μ -SQUID detector on the prong and the electrical connections. The power dissipated in the tuning fork sensor comes from two sources: the excitation and the vibration of the tuning fork. The tuning fork is excited mechanically by a thickness mode piezocrystal of 1 nF capacitance excited by a voltage of 10 mV_{rms} amplitude, resulting in 2 nW of dissipated power. Dissipation due to the vibration of the tuning fork can be estimated from the current generated by the tuning fork: taking the impedance at resonance, $R_{res}=25 \text{ K}\Omega$ for our tuning fork, a generated current of 1 nA gives a dissipated power of 0.025 pW. These values are compatible with the use of the tuning fork μ -SQUID sensor in a very low temperature scanning microscope.

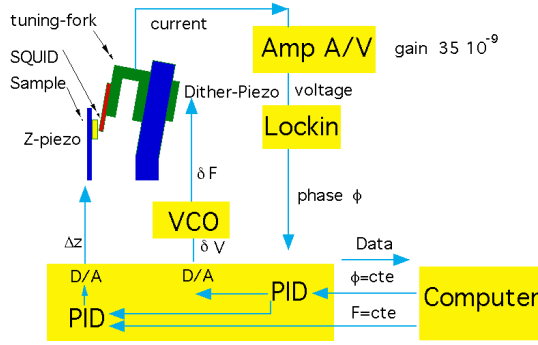


FIG. 4: Diagram of the frequency and distance regulation used for our SSFM.

IV. REGULATION SCHEME

The magnetic field due to the vortices spreads rapidly with height. Therefore a large scan range is necessary in order to observe a sufficient number of vortices. As a consequence the microscope needs to be much more flexible than standard AFM or STM microscopes imaging smaller surfaces. The scanner used [18] has a scan range of $60 \mu\text{m}$ at low temperatures for 200 V applied voltage. The eigenfrequency of the scanner is of the order of 200 Hz, limiting the bandwidth of regulation. We have adopted a regulation scheme using a phase locked loop constituted of discrete elements [14].

The increase of the resonance frequency for increasing surface forces is used for the approach control. A working frequency is chosen 1 Hz higher than the resonance frequency far away from the sample surface. The phase of the tuning fork current is offset to be zero at resonance. The tuning fork is excited by a piezoelectric thickness mode plate via a voltage controlled oscillator (VCO), (Yokogawa FE 200), the excitation frequency is adjusted continuously using the condition that the phase must be kept at a fixed value (phase value at resonance). The tip-sample distance is fixed by the condition that the excitation frequency must be equal to the working frequency. These two constraints: maintaining the phase locked, and stabilizing the resonance frequency value, can be satisfied by cascading two Proportional-Integral (PI) stages, Fig. 4. The first, maintains the oscillator at resonance in locking the phase, the second stage uses the deviation of the resonance frequency from the working frequency to act through a D/A converter on the piezoelectric z-bender, moving the sample in or out. The working frequency is set via a digital input, the analog input takes the phase output of the digital lockin-amplifier (Perkin Elmer 7280). The PI stages are programmed in a PLD device [26], driven by a 40 MHz clock. The numeric PI stages have a frequency bandwidth of about 10 kHz.

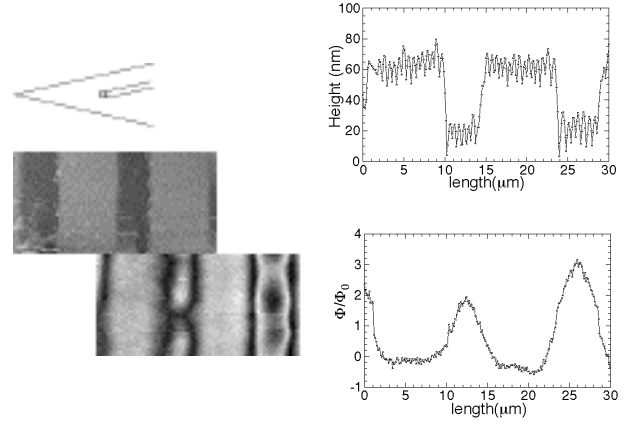


FIG. 5: left top: Schematic drawing of the μ -SQUID -chip used, the magnetic sensor was $15 \mu\text{m}$ away from the tip. left center: Topographic image of a periodic pattern of $6 \mu\text{m}$ wide Nb lines (clear) $8 \mu\text{m}$ apart, the image is $28 \mu\text{m}$ wide and $14 \mu\text{m}$ high. left bottom: Magnetic image taken simultaneously ($\mu_0 H_{ext} = 1 \text{ mT}$, field cooled). The pictures are laterally offset to reflect the μ -SQUID -tip distance, right top: Line scan through the topographic image, right bottom: Line scan through the magnetic image.

V. PERFORMANCE AND RESULTS

The μ -SQUID itself is scanned in close proximity to the sample's surface. μ -SQUIDS are of such a small size that it is impractical to couple flux to the μ -SQUID with a flux transformer, a flux locked loop technique can not be used. In presence of strong signals the μ -SQUID's critical current varies over several arches of period Φ_0 , and the total flux variation may be obtained by integration of this variation.

The geometry of the refrigerator allows thermalization of the microscope on any stage. In the first example we used a Nb μ -SQUID patterned from 30 nm thick film having a superconducting transition temperature of 7.8 K. The microscope plate was mounted on the 4.2 K stage. The sample consisted of $6 \mu\text{m}$ wide Nb lines $8 \mu\text{m}$ apart. The lines were obtained by an RIE process from a UHV e-beam deposited Nb film of 50 nm thickness. The sample was mounted on the scanner. We present topographic and magnetic images and line scans, Fig. 5. The probe was cut with the dicing machine. The μ -SQUID was about $15 \mu\text{m}$ away from the tip, the angle of approach was ≈ 10 degrees, resulting in a μ -SQUID -sample distance of $2.6 \mu\text{m}$. For imaging the sample was cooled in a perpendicularly applied field of 1 mT and the sample temperature was 5 K. The μ -SQUID temperature was regulated at 6.7 K. At this temperature the Nb- μ -SQUIDS critical current was $400 \mu\text{A}$ with $40 \mu\text{A}$ modulation ($I_c(\Phi_0) - I_c(\Phi_0/2)$).

The magnetic image obtained is due to screening currents in the superconducting lines. The magnetic spatial resolution is limited by the width of the Nb lines and the μ -SQUID -sample distance. The topographic image is displaced compared to the magnetic image due to the μ -

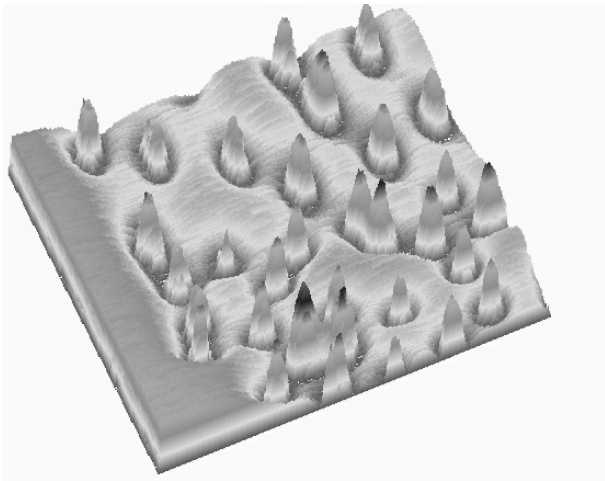


FIG. 6: Magnetic flux image of a 200 nm thin Nb film at 0.9 K as measured with the Scanning μ -SQUID Force Microscope (SSFM). Each peak is due to a flux quantum produced by a single vortex. The image size is $28 \times 28 \mu\text{m}^2$, each pixel has been recorded after averaging 20 μ -SQUID readings.

SQUID -tip distance Fig. 5 left top. On principle the lateral resolution of the microscope is limited by the shape of the tip: The sensor cannot probe steep profiles without touching elsewhere, as the tip is just the apex of the chip and the approach angle is small. For example, with an approach angle of 10 degrees and a step height of 50 nm the chip will start to sense the step 300 nm before the apex reaches the step.

For high resolution measurements we used Al- μ -SQUIDS ($T_c=1.2$ K) and placed the microscope plate on the still screen. A critical current modulation between $120 \mu\text{A}$ at $\Phi_{ext}=\Phi_0/2$ and $170 \mu\text{A}$ at $\Phi_{ext}=\Phi_0$ was obtained at 0.45 K. The μ -SQUID operating temperature of 0.45 K was reached using silver foil as thermal link between mixing chamber and the thermally isolated μ -SQUID head. The μ -SQUID chip was precision-cut at about $10 \mu\text{m}$ from the tip, no mesa etch was applied. The angle of approach was 5 degrees. The μ -SQUID was used to study a continuous Nb thin film of 200 nm thickness, evaporated in UHV with an electron beam evaporator and mounted on the scanner, thermalized at 0.9 K.

The μ -SQUID magnetic image, Fig. 6, shows the spatial dependence of the μ -SQUID's critical current after field cooling the film in 0.1 mT. The expected average vortex density for such a field is one vortex in $20.7 \mu\text{m}^2$. The image size is $28 \mu\text{m}$ a side. We measure the expected vortex density. Each imaged vortex is circled by a line of minimum critical current. This is due to the fact that the flux variations measured causes the μ -SQUID's critical current to pass through a minimum of the $I_c(\Phi)$ characteristic. The measured $I_c(\Phi)$ characteristic can be used to translate the critical current- into the flux variation. The Nb film showed strong pinning as the vortex pattern did not change upon an applied field change of 0.1 mT at low temperatures in the superconducting state.

Fig. 7 shows a line scan through a vortex of Fig. 6. Here we corrected for the periodic $I_c(\Phi)$ characteristic. We obtain a well defined bell-shaped curve. The noise level is about $5 \cdot 10^{-3} \Phi_0$ corresponding to $10^{-3} \Phi_0 / \sqrt{Hz}$. The width at half height is $2 \mu\text{m}$. This width is due to the instrumental resolution determined by the distance between the μ -SQUID and the sample's surface.

A more quantitative mean to analyze one single vortex is to fit the measured flux profile to the expected flux profile of a single vortex, for a given μ -SQUID size and μ -SQUID -sample distance. Nb as a thin film is a type II superconductor with a normal vortex core diameter of about 20 nm (coherence length, ξ). In the limit of a small vortex core diameter, compared to the penetration length and the μ -SQUID -sample distance, it is possible to use an analytical expression [27] for the z component of the magnetic field produced by a vortex. The field is calculated at a height z above the center of the film of arbitrary film thickness d, assuming that the core diameter $\rightarrow 0$. This approximation is valid as the μ -SQUID sample distance is of the order of $1 \mu\text{m}$, making it impossible for us to resolve the core of a vortex in Nb. The expression for the field is:

$$h_z(\mathbf{r}, z) = \frac{\Phi_0}{(2\pi\lambda_{ab})^2} \int d^2\mathbf{k} \exp^{i\mathbf{k}\mathbf{r}} \frac{\exp^{k(d/2-z)}}{\alpha[\alpha + k \coth(\alpha d/2)]} \quad (2)$$

where $\mathbf{r} = \{x, y\}$, $\mathbf{k} = \{k_x, k_y\}$, $k = \sqrt{k_x^2 + k_y^2}$ and $\alpha = \sqrt{k^2 + \lambda^{-2}}$.

After integrating the spatial dependence of the predicted magnetic field over the μ -SQUID's surface it is possible to compare the measured flux profile with the calculated one. The adjustable parameters are λ and to a certain degree the μ -SQUID -sample distance.

A height between of 0.8 and $1.3 \mu\text{m}$ corresponding to 9 and $15 \mu\text{m}$ μ -SQUID -tip, is consistent with our observations for this particular sensor. A penetration depth of 100 to 200 nm is expected for Nb thin films of good quality of comparable thickness. The two different fits presented in Fig. 7 are limiting cases considering the uncertainty of the μ -SQUID -sample distance. They show also how the μ -SQUID -sample distance intervenes in the interpretation of the absolute value of the physical quantity reflecting the magnetic field source (penetration depth).

VI. DISCUSSION

We have built a scanning μ -SQUID force microscope capable of imaging individual vortices with high magnetic and spatial resolution. The spatial resolution obtained is the best reported for SQUID microscopes. The microscope is based on a combination of the lithographically defined μ -SQUID -detector with the force sensor. The force sensor is a quartz tuning fork with a power dissipation in the nW range, well adapted for use at low temperatures. We have demonstrated that this microscope

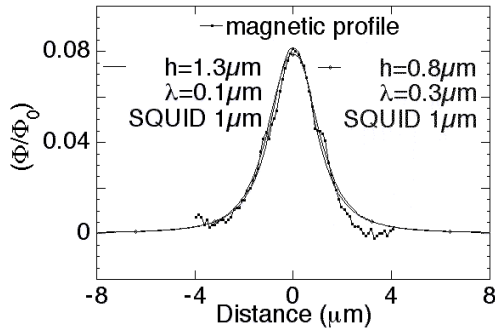


FIG. 7: Flux profile of a vortex in the Nb film normalized by the quantum of flux of the μ -SQUID. The two different fits represent the uncertainty in height due to the uncertainty of μ -SQUID -tip distance. The value for the penetration depth, λ , obtained from equation 2, is strongly dependent on the scan height.

has state of the art magnetic imaging capabilities combined with topographic imaging at temperatures as low as 0.45 K. Improvements of the thermal isolation will allow us to image even at lower temperatures. The spatial and magnetic resolution of the μ -SQUID sensor can still be improved. The mesa etch technique demonstrated in Fig. 2 reduces the μ -SQUID sample distance to less than $0.5 \mu\text{m}$. When this short distance is attained the spatial resolution [21] is given by the 200 nm width of the μ -

SQUID branch. The sensitivity of the μ -SQUID is limited by the measuring scheme, in shunting the μ -SQUID it is possible to increase the measuring frequency and thus to increase sensitivity. The microscope is working in a dilution refrigerator at 0.45 K, opening new possibilities for the direct observation of vortices in unconventional LT_c superconductors and to answer questions like: How does the vortex lattice of UPt_3 respond upon the crossing of the phase boundaries inside the superconducting phase diagram? Vortex phase transitions in microstructured lattices can be studied, leading to the understanding of the underlying coherence and frustration effects.

One key aspect of the microscope is the combination of tuning fork and the microfabricated μ -SQUID sensor. This modular approach can be easily transferred to other types of microfabricated devices as Hall probes or single electron transistor sensors for example.

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- [1] S. J. Bending, *Advances in Physics* **48**, 449 (1999).
 - [2] H. J. Hug, B. Stiefel, P. J. A. van Schendel, A. Moser, S. Martin and H.-J. Guntherodt, *Rev. Sci. Instrum.* **70**, 3625, (1999).
 - [3] A. Volodin, K. Temst, C. Van Haesendonck, and Y. Bruynseraede, *Rev. Sci. Instrum.* **71**, 4468, (2000).
 - [4] A. Oral, S. J. Bending, M. Henini, *Appl. Phys. Lett.* **69**, 1324 (1996).
 - [5] J. R. Kirtley, M. B. Ketchen, K. G. Stawiasz, J. Z. Sun, W. J. Gallagher, S. H. Blanton and S. J. Wind, *Appl. Phys. Lett.* **66**, 1138 (1995).
 - [6] F.C. Wellstood, Y. Gim, A. Amar, R.C. Black and A. Mathai, *IEEE Trans. Appl. Supercond.* **7** 3134 (1997).
 - [7] T. S. Lee, E. Dantsker and J. Clarke, *Rev. Sci. Instrum.* **69**, 4208 (1998).
 - [8] T. Morooka, S. Nakayama, A. Odawara and K. Chinon, *Jap. J. Appl. Phys.* **38**, L119-22., (1999).
 - [9] L. N. Vu, M. S. Wistrom and D. J. Van Harlingen, *Appl. Phys. Lett.* **63**, 1693, (1993).
 - [10] B. W. Gardner, J. C. Wynn, P. G. Björnsson, E. W. J. Straver, K. Moler, J. R. Kirtley and M. B. Ketchen, *Rev. Sci. Instrum.* **72**, 2361, (2000).
 - [11] T. Schweinböck, D. Weiss, M. Lipinski and K. Eberl, *J. Appl. Phys.* **87**, 6496, (2000).
 - [12] K. Karrei and R. D. Grober, *Appl. Phys. Lett.* **66**, 1744, (1995).
 - [13] F. J. Giessibl, *Appl. Phys. Lett.* **76**, 1470 (2000).
 - [14] J. Rychen, T. Ihn, P. Studerus, A. Hermann and K. Ensslin, *Rev. Sci. Instrum.* **70**, 2765, (1999).
 - [15] J. Rychen, T. Ihn, P. Studerus, A. Hermann, K. Ensslin, H. J. Hug, P. J. A. van Schendel and H.-J. Guntherodt, *Rev. Sci. Instrum.* **71**, 1695, (2000).
 - [16] R. D. Grober, J. Acimovic, J. Schuck, D. Hessman, P. J. Kindlemann, J. Hespanha, A. S. Morse, K. Karrei, I. Tiemann and S. Manus, *Rev. Sci. Instrum.* **71**, 2776 (2000).
 - [17] The cryostat has been designed at the CRTBT-CNRS by A. Benoit and M. Caussignac. The same is now commercialized by l'Air Liquide, DTA, Sassenage (France).
 - [18] J. Siegel, J. Witt, N. Venturi and S. B. Field, *Rev. Sci. Instrum.* **66**, 2520 (1995).
 - [19] E. du Tremolet de Lacheisserie, *Revue de Physique Applique*, **10**, 169, (1975).
 - [20] P. W. Kolb, R. S. Decca and H. D. Drew, *Rev. Sci. Instrum.* **69**, 310 (1998).
 - [21] K. Hasselbach, C. Veauvy and D. Mailly, *Physica C* **332**, 140, (2000).
 - [22] C. Chapelier, M. El Khatib, P. Perrier, A. Benoit and D. Mailly *Superconducting Devices and their Applications* Eds H. Koch, H. Lübbig Springer Berlin **31**, 286 (1992).
 - [23] W. Wernsdorfer, E. Bonet Orozco, K. Hasselbach, A. Benoit, N. Demoncy, A. Loiseau, H. Pascard and D. Mailly, *Phys. Rev. Lett.* **78**, 1791 (1997).
 - [24] Gamberini SARL, CROLLES, France.

- [25] F. Ayela, J. L. Bret, J. Chaussy, T. Fournier and E. Mngaz, *Rev. Sci. Instrum.* **71**, 2211, (2000).
- [26] Altera Corporation, 101 Innovation Drive, San Jose, California 95134, USA.
- [27] J.R. Kirtley, C. C. Tsuei, K. A. Molar, V. G. Kogan, J. R. Clem and A. J. Turberfield, *Appl. Phys. Lett.* **74**, 4011, (1999) and references there in.